



FOR IMMEDIATE RELEASE

Contacts:

Aehr Test Systems

Carl Buck
V.P. of Marketing
(510) 623-9400 x381

Financial Relations Board

Marilynn Meek
Analyst/Investor Contact
(212) 827-3773

Alliance ATE Consulting Group

William Wymbs
CEO
(408) 230-9711

AEHR TEST SYSTEMS ANNOUNCES PARTNERSHIP WITH ALLIANCE ATE CONSULTING GROUP

Fremont, CA (November 5, 2012) - Aehr Test Systems (Nasdaq: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, and AllianceATE Consulting Group (AllianceATE), a semiconductor software and test services company, announced a partnership today to add Alliance ATE's VelocityCAE software as an option to Aehr Test's ABTS™ advanced burn-in and test systems.

VelocityCAE is a test program, vector and timing generation tool suite developed by AllianceATE. VelocityCAE takes EDA Simulation design files and translates them into complete test programs for use on Aehr Test's ABTS system.

“Our partnership with Aehr combines the design-to-test capabilities of VelocityCAE with Aehr Test's burn-in technology to help meet the evolving needs of semiconductor companies,” said Bill Wymbs, CEO at AllianceATE. “We believe that our expertise in both test program and vector translation complements Aehr's state-of-the-art capabilities in the burn-in and test market.”

Test engineers typically use industry-standard WGL (Waveform Generation Language) and STIL (Standard Test Interface Language) vector formats to run tests on semiconductor devices during both product characterization and production test. To increase test coverage and reduce time-to-market, semiconductor companies are now using these same vector formats during the burn-in process. VelocityCAE software from AllianceATE will convert WGL and STIL vectors to run on Aehr Test's ABTS test and burn-in systems, making test program development more efficient and decreasing time-to-market.

“Semiconductor companies are asking for more functional test capabilities both during the burn-in stage with our ABTS system and in wafer sort with our FOX™ full-wafer test system,” said Carl Buck, vice president of marketing at Aehr Test Systems. “We are excited to be able to partner with AllianceATE to provide our customers with a better way to generate both test

vectors and test programs so that they have a faster time to market. These capabilities are increasingly important, as the latest ABTS system has a full functional test sequencer backed by 32 million vectors to exercise the devices under test.”

Aehr Test will also offer an advanced version of VelocityCAE to their customers, which includes full automated test program generation from product engineering spreadsheets, which will decrease time-to-market further.

The ABTS family of products is based on a new hardware and software architecture that is designed to address not only today’s devices, but also future devices for many years to come. It can test and burn-in both logic and memory devices, including resources for high pin-count devices and configurations for high-power and low-power applications. The ABTS system can be configured with up to 72 burn-in boards with up to 320 I/O channels each and 32M of test vector memory per channel. The ABTS system is optimized for use with the Sensata iSocket* Thermal Management Technology, which provides a scalable cost-effective solution using individual device temperature control for ICs up to 75 watts or more. Individual temperature control enables high-power devices with a broad range of power dissipation to be burned-in simultaneously in a single burn-in chamber while maintaining a precise device temperature. The ABTS system also uses N+1 redundancy technology for many key components in the system to maximize system uptime.

*iSocket is a trademark of Sensata Technologies, Inc.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS and FOX families of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s website at www.aehr.com.

About Alliance ATE Consulting Group

Based in the heart of Silicon Valley, AllianceATE Consulting Group, Inc is a semiconductor software and test services company that automates the design-to-test processes. Alliance ATE can deliver turnkey production test solutions targeted at a variety of test platforms and contract manufacturers. VelocityCAE software was developed by AllianceATE to reduce time-to-market of complex semiconductor device test solutions while reducing test development cost by orders of magnitude. For more information visit www.allianceate.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

###